



# STW9N150

N-channel 1500 V - 1.8  $\Omega$  - 8 A - TO-247  
very high voltage PowerMESH™ Power MOSFET

## Features

| Type     | V <sub>DSS</sub> | R <sub>DS(on)</sub> | I <sub>D</sub> | P <sub>w</sub> |
|----------|------------------|---------------------|----------------|----------------|
| STW9N150 | 1500 V           | < 2.5 $\Omega$      | 8 A            | 320 W          |

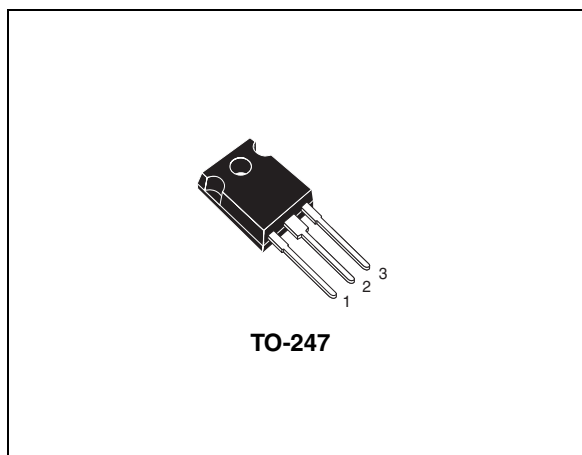
- 100% avalanche tested
- Avalanche ruggedness
- Gate charge minimized
- Very low intrinsic capacitances
- High speed switching
- Very low on-resistance

## Application

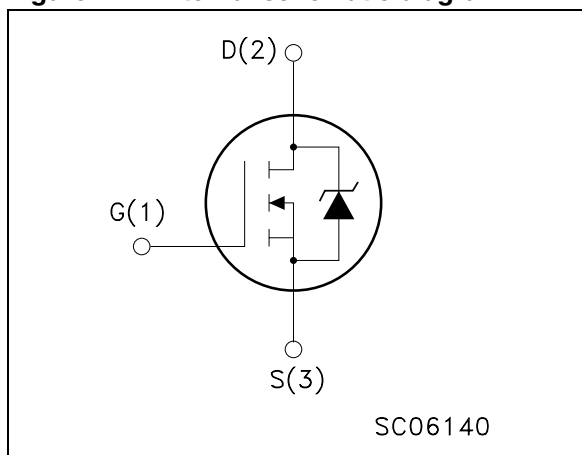
- Switching applications

## Description

Using the well consolidated high voltage MESH OVERLAY™ process, STMicroelectronics has designed an advanced family of Power MOSFETs with outstanding performances. The strengthened layout coupled with the company's proprietary edge termination structure, gives the lowest R<sub>DS(on)</sub> per area, unrivalled gate charge and switching characteristics.



**Figure 1. Internal schematic diagram**



**Table 1. Device summary**

| Order code | Marking | Package | Packaging |
|------------|---------|---------|-----------|
| STW9N150   | 9N150   | TO-247  | Tube      |

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# 1 Electrical ratings

**Table 2. Absolute maximum ratings**

| Symbol             | Parameter                                                         | Value      | Unit                  |
|--------------------|-------------------------------------------------------------------|------------|-----------------------|
| $V_{DS}$           | Drain-source voltage ( $V_{GS} = 0$ )                             | 1500       | V                     |
| $V_{GS}$           | Gate- source voltage                                              | $\pm 30$   | V                     |
| $I_D$              | Drain current (continuous) at $T_C = 25\text{ }^{\circ}\text{C}$  | 8          | A                     |
| $I_D$              | Drain current (continuous) at $T_C = 100\text{ }^{\circ}\text{C}$ | 5          | A                     |
| $I_{DM}^{(1)}$     | Drain current (pulsed)                                            | 32         | A                     |
| $P_{TOT}$          | Total dissipation at $T_C = 25\text{ }^{\circ}\text{C}$           | 320        | W                     |
|                    | Derating factor                                                   | 2.56       | W/ $^{\circ}\text{C}$ |
| $T_J$<br>$T_{stg}$ | Operating junction temperature<br>Storage temperature             | -55 to 150 | $^{\circ}\text{C}$    |

1. Pulse width limited by safe operating area

**Table 3. Thermal data**

| Symbol         | Parameter                                      | Value | Unit                        |
|----------------|------------------------------------------------|-------|-----------------------------|
| $R_{thj-case}$ | Thermal resistance junction-case max           | 0.39  | $^{\circ}\text{C}/\text{W}$ |
| $R_{thj-amb}$  | Thermal resistance junction-ambient max        | 50    | $^{\circ}\text{C}/\text{W}$ |
| $T_J$          | Maximum lead temperature for soldering purpose | 300   | $^{\circ}\text{C}/\text{W}$ |

**Table 4. Avalanche characteristics**

| Symbol   | Parameter                                                                                                                 | Max value | Unit |
|----------|---------------------------------------------------------------------------------------------------------------------------|-----------|------|
| $I_{AR}$ | Avalanche current, repetitive or not-repetitive<br>(pulse width limited by $T_J$ max)                                     | 8         | A    |
| $E_{AS}$ | Single pulse avalanche energy<br>(starting $T_J = 25\text{ }^{\circ}\text{C}$ , $I_D = I_{AR}$ , $V_{DD} = 50\text{ V}$ ) | 720       | mJ   |

## 2 Electrical characteristics

(T<sub>case</sub> = 25 °C unless otherwise specified)

**Table 5. On /off states**

| Symbol        | Parameter                                        | Test conditions                                                                       | Min. | Typ. | Max.      | Unit                           |
|---------------|--------------------------------------------------|---------------------------------------------------------------------------------------|------|------|-----------|--------------------------------|
| $V_{(BR)DSS}$ | Drain-source breakdown voltage                   | $I_D = 1 \text{ mA}$ , $V_{GS} = 0$                                                   | 1500 |      |           | V                              |
| $I_{DSS}$     | Zero gate voltage drain current ( $V_{GS} = 0$ ) | $V_{DS} = \text{Max rating}$<br>$V_{DS} = \text{Max rating}$ , $T_C = 125 \text{ °C}$ |      |      | 10<br>500 | $\mu\text{A}$<br>$\mu\text{A}$ |
| $I_{GSS}$     | Gate-body leakage current ( $V_{DS} = 0$ )       | $V_{GS} = \pm 30 \text{ V}$                                                           |      |      | $\pm 100$ | nA                             |
| $V_{GS(th)}$  | Gate threshold voltage                           | $V_{DS} = V_{GS}$ , $I_D = 250 \mu\text{A}$                                           | 3    | 4    | 5         | V                              |
| $R_{DS(on)}$  | Static drain-source on resistance                | $V_{GS} = 10 \text{ V}$ , $I_D = 4 \text{ A}$                                         |      | 1.8  | 2.5       | $\Omega$                       |

**Table 6. Dynamic**

| Symbol                              | Parameter                                                               | Test conditions                                                                                 | Min. | Typ.                 | Max. | Unit           |
|-------------------------------------|-------------------------------------------------------------------------|-------------------------------------------------------------------------------------------------|------|----------------------|------|----------------|
| $g_{fs}^{(1)}$                      | Forward transconductance                                                | $V_{DS} = 15 \text{ V}$ , $I_D = 4 \text{ A}$                                                   |      | 7.5                  |      | S              |
| $C_{iss}$<br>$C_{oss}$<br>$C_{rss}$ | Input capacitance<br>Output capacitance<br>Reverse transfer capacitance | $V_{DS} = 25 \text{ V}$ , $f = 1 \text{ MHz}$ , $V_{GS} = 0$                                    |      | 3255<br>294<br>22.4  |      | pF<br>pF<br>pF |
| $C_{oss \text{ eq.}}$               | Equivalent Output capacitance                                           | $V_{GS} = 0$ , $V_{DS} = 0 \text{ to } 1200 \text{ V}$                                          |      | 118                  |      | pF             |
| $R_g$                               | Gate input resistance                                                   | $f = 1 \text{ MHz}$ Gate DC Bias = 0<br>Test signal level = 20 mV<br>open drain                 |      | 2.4                  |      | $\Omega$       |
| $Q_g$<br>$Q_{gs}$<br>$Q_{gd}$       | Total gate charge<br>Gate-source charge<br>Gate-drain charge            | $V_{DD} = 1200 \text{ V}$ , $I_D = 8 \text{ A}$ ,<br>$V_{GS} = 10 \text{ V}$<br>(see Figure 15) |      | 89.3<br>15.8<br>50.4 |      | nC<br>nC<br>nC |

1. Pulsed: Pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%

**Table 7. Switching times**

| Symbol       | Parameter           | Test conditions                                                                                                   | Min. | Typ. | Max | Unit |
|--------------|---------------------|-------------------------------------------------------------------------------------------------------------------|------|------|-----|------|
| $t_{d(on)}$  | Turn-on delay time  | $V_{DD} = 750\text{ V}$ , $I_D = 4\text{ A}$ ,<br>$R_G = 4.7\ \Omega$ , $V_{GS} = 10\text{ V}$<br>(see Figure 14) |      | 41   |     | ns   |
| $t_r$        | Rise time           |                                                                                                                   |      | 14.7 |     | ns   |
| $t_{d(off)}$ | Turn-off-delay time |                                                                                                                   |      | 86   |     | ns   |
| $t_f$        | Fall time           |                                                                                                                   |      | 52   |     | ns   |

**Table 8. Source drain diode**

| Symbol          | Parameter                     | Test conditions                                                                                                                             | Min. | Typ. | Max | Unit          |
|-----------------|-------------------------------|---------------------------------------------------------------------------------------------------------------------------------------------|------|------|-----|---------------|
| $I_{SD}$        | Source-drain current          |                                                                                                                                             |      |      | 8   | A             |
| $I_{SDM}^{(1)}$ | Source-drain current (pulsed) |                                                                                                                                             |      |      | 32  | A             |
| $V_{SD}^{(2)}$  | Forward on voltage            | $I_{SD} = 8\text{ A}$ , $V_{GS} = 0$                                                                                                        |      |      | 1.6 | V             |
| $t_{rr}$        | Reverse recovery time         | $I_{SD} = 8\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$<br>$V_{DD} = 60\text{ V}$<br>(see Figure 16)                                     |      | 988  |     | ns            |
| $Q_{rr}$        | Reverse recovery charge       |                                                                                                                                             |      | 9.5  |     | $\mu\text{C}$ |
| $I_{RRM}$       | Reverse recovery current      |                                                                                                                                             |      | 19.3 |     | A             |
| $t_{rr}$        | Reverse recovery time         | $I_{SD} = 8\text{ A}$ , $di/dt = 100\text{ A}/\mu\text{s}$<br>$V_{DD} = 60\text{ V}$ , $T_J = 150\text{ }^\circ\text{C}$<br>(see Figure 16) |      | 884  |     | ns            |
| $Q_{rr}$        | Reverse recovery charge       |                                                                                                                                             |      | 8.2  |     | $\mu\text{C}$ |
| $I_{RRM}$       | Reverse recovery current      |                                                                                                                                             |      | 18.6 |     | A             |

1. Pulse width limited by safe operating area

2. Pulsed: pulse duration = 300  $\mu\text{s}$ , duty cycle 1.5%

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

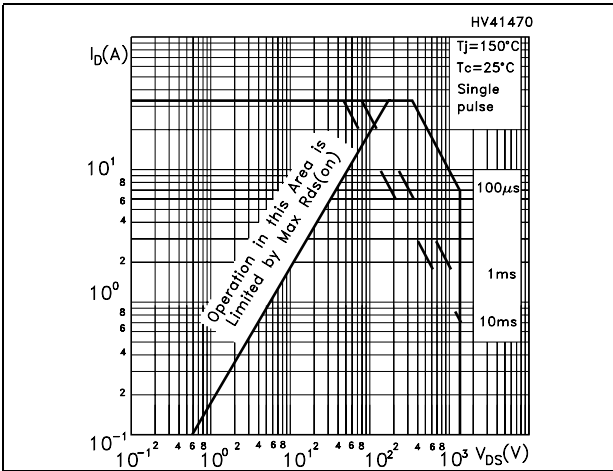


Figure 3. Thermal impedance

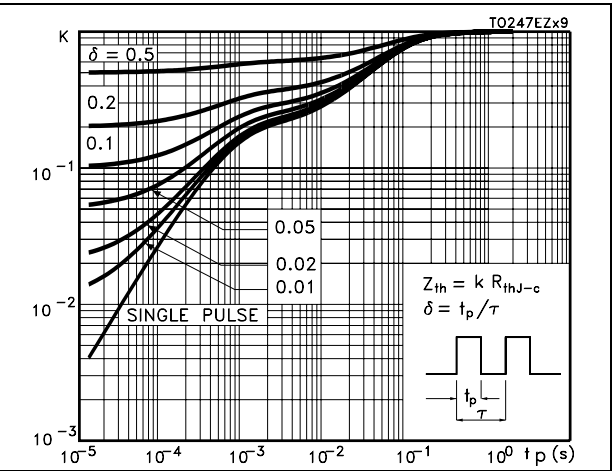


Figure 4. Output characteristics

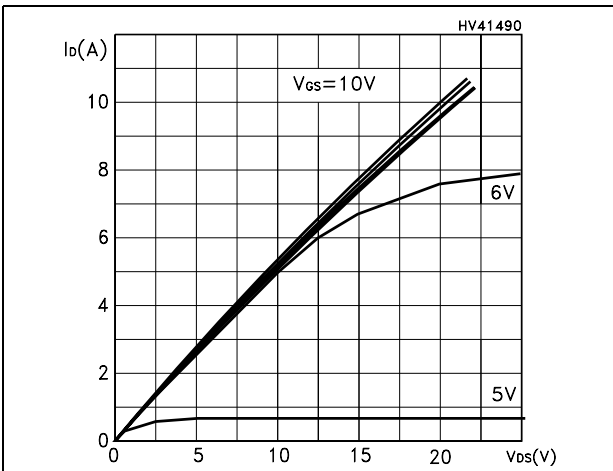


Figure 5. Transfer characteristics

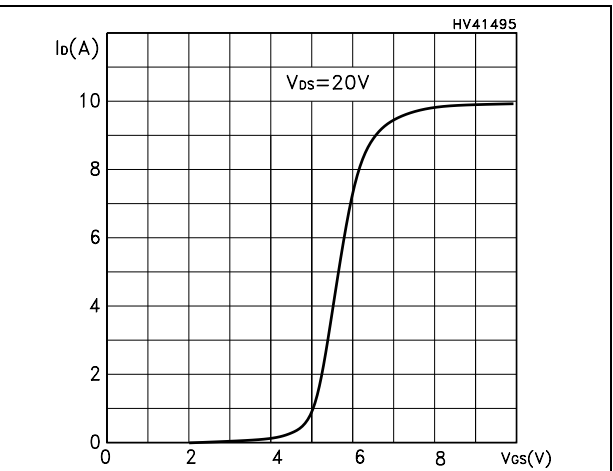


Figure 6. Normalized BV<sub>DSS</sub> vs temperature

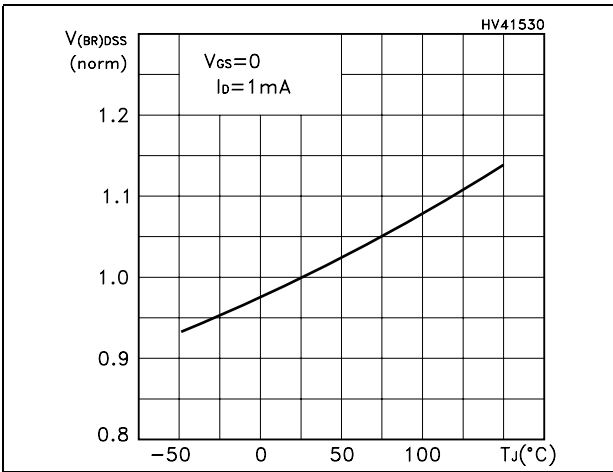


Figure 7. Static drain-source on resistance

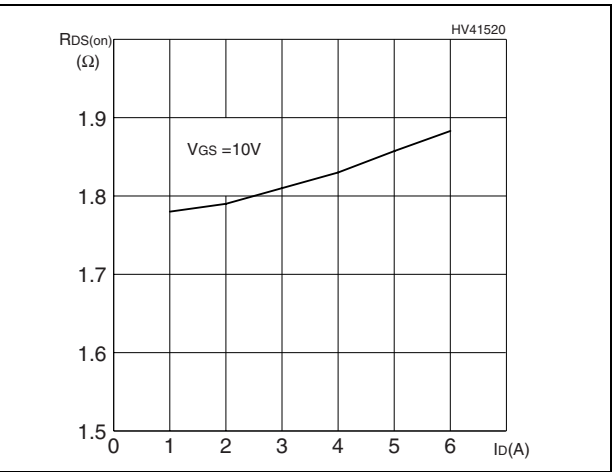


Figure 8. Gate charge vs gate-source voltage Figure 9. Capacitance variations

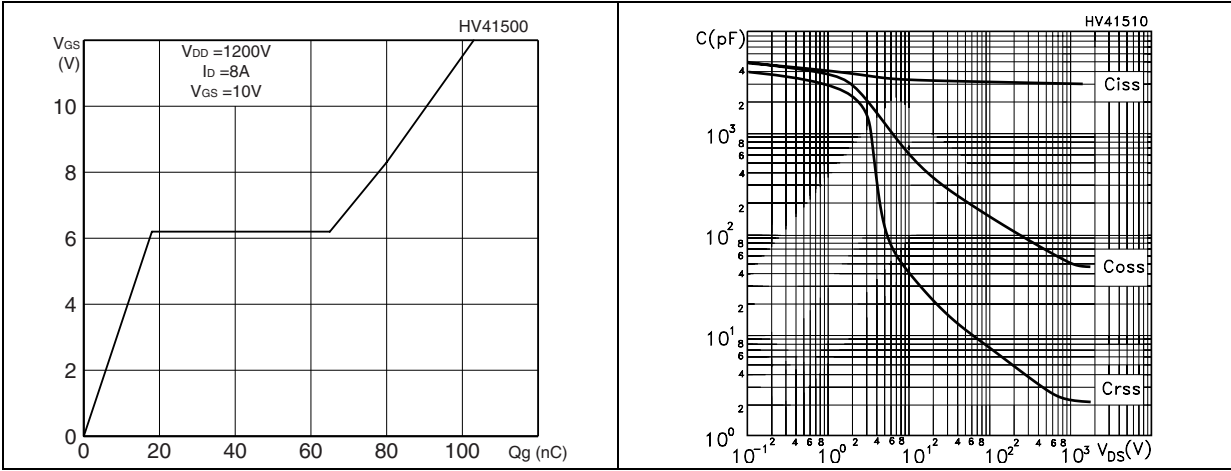


Figure 10. Normalized gate threshold voltage vs temperature Figure 11. Normalized on resistance vs temperature

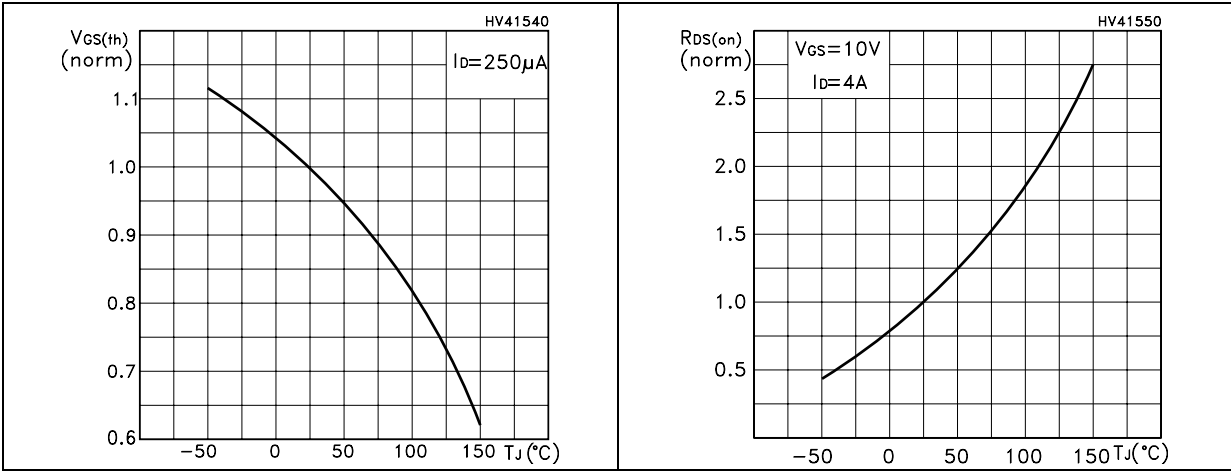
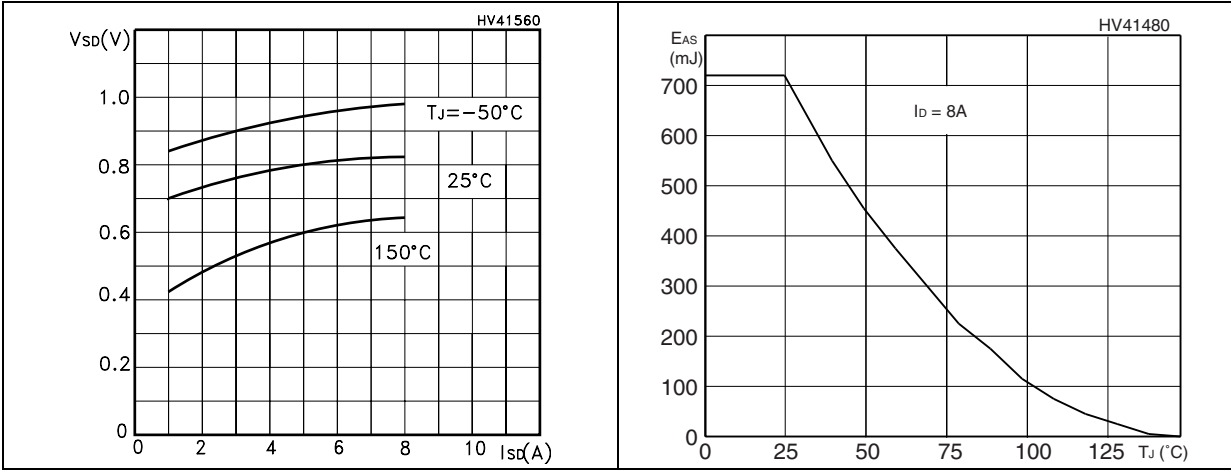
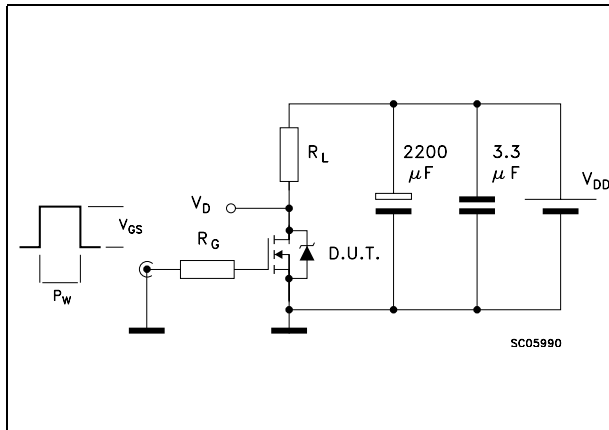


Figure 12. Source-drain diode forward characteristics Figure 13. Maximum avalanche energy vs temperature

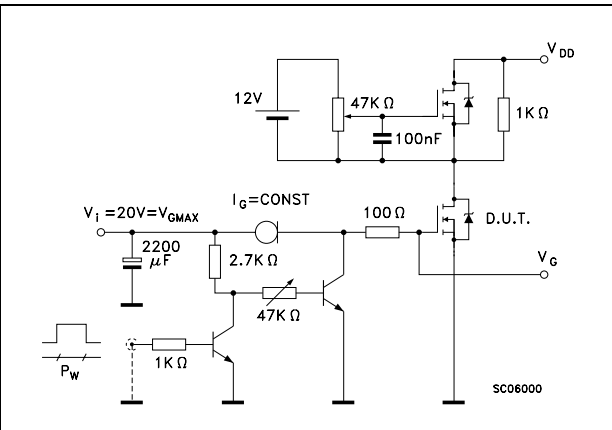


### 3 Test circuits

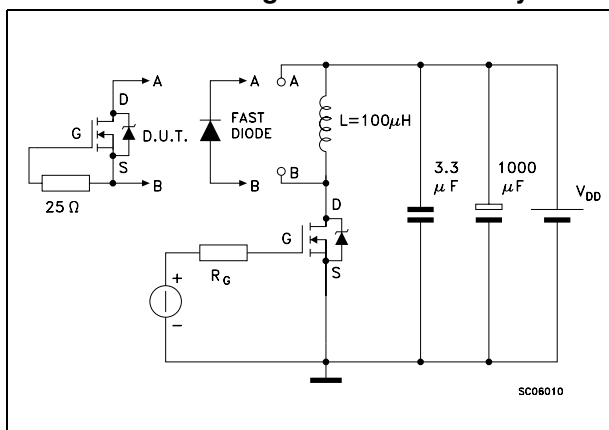
**Figure 14. Switching times test circuit for resistive load**



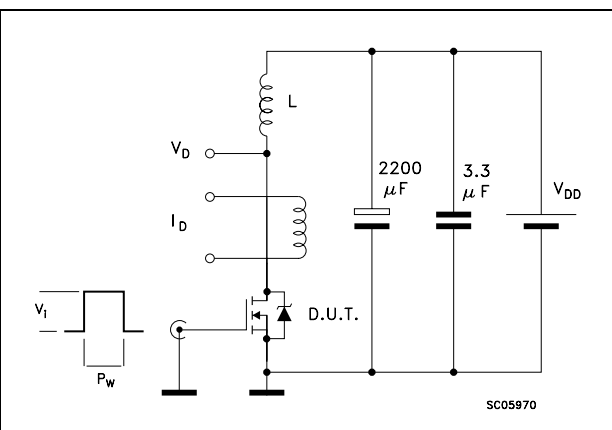
**Figure 15. Gate charge test circuit**



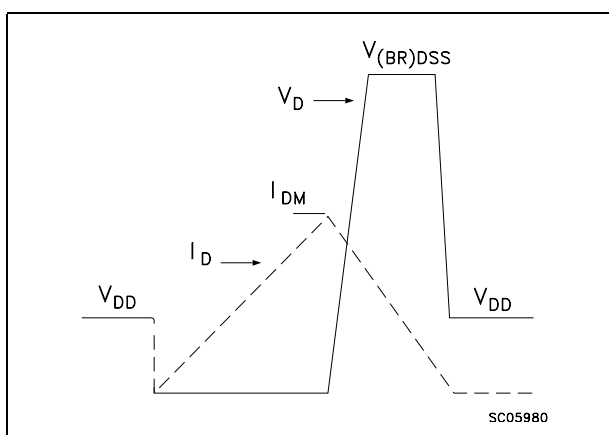
**Figure 16. Test circuit for inductive load switching and diode recovery times**



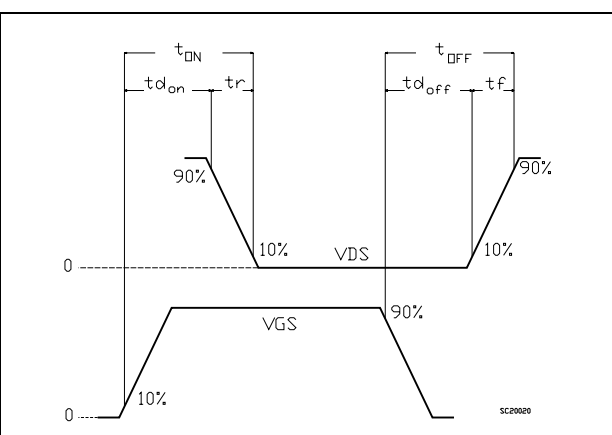
**Figure 17. Unclamped Inductive load test circuit**



**Figure 18. Unclamped inductive waveform**



**Figure 19. Switching time waveform**

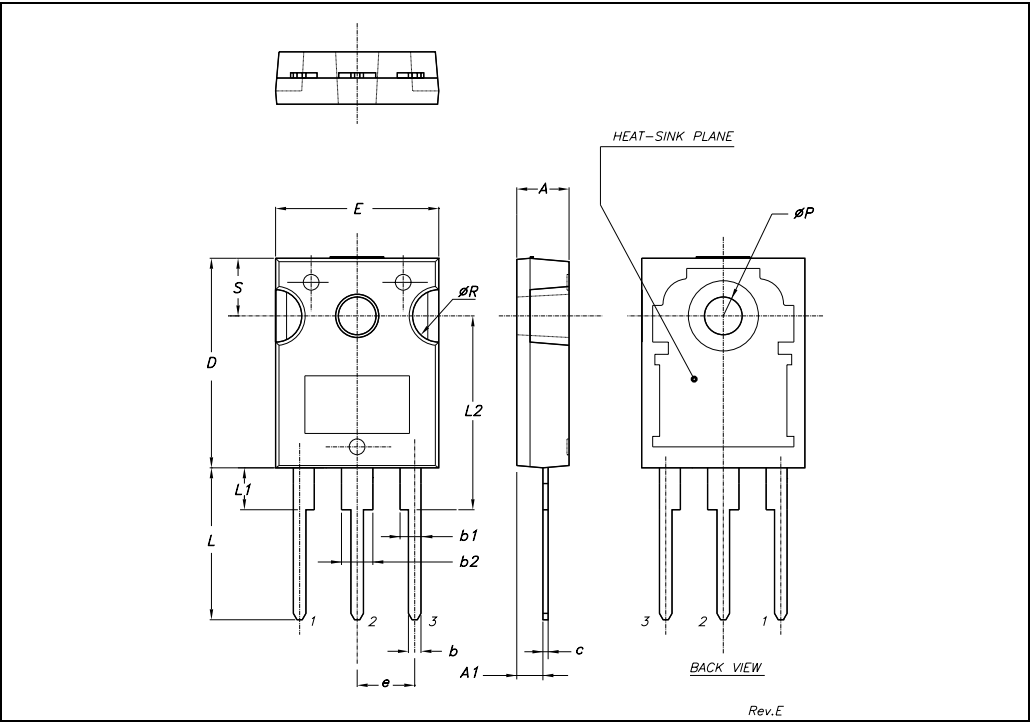


## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect. The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: [www.st.com](http://www.st.com)

TO-247 MECHANICAL DATA

| DIM. | mm.   |       |       | inch  |       |       |
|------|-------|-------|-------|-------|-------|-------|
|      | MIN.  | TYP.  | MAX.  | MIN.  | TYP.  | MAX.  |
| A    | 4.85  |       | 5.15  | 0.19  |       | 0.20  |
| A1   | 2.20  |       | 2.60  | 0.086 |       | 0.102 |
| b    | 1.0   |       | 1.40  | 0.039 |       | 0.055 |
| b1   | 2.0   |       | 2.40  | 0.079 |       | 0.094 |
| b2   | 3.0   |       | 3.40  | 0.118 |       | 0.134 |
| c    | 0.40  |       | 0.80  | 0.015 |       | 0.03  |
| D    | 19.85 |       | 20.15 | 0.781 |       | 0.793 |
| E    | 15.45 |       | 15.75 | 0.608 |       | 0.620 |
| e    |       | 5.45  |       |       | 0.214 |       |
| L    | 14.20 |       | 14.80 | 0.560 |       | 0.582 |
| L1   | 3.70  |       | 4.30  | 0.14  |       | 0.17  |
| L2   |       | 18.50 |       |       | 0.728 |       |
| øP   | 3.55  |       | 3.65  | 0.140 |       | 0.143 |
| øR   | 4.50  |       | 5.50  | 0.177 |       | 0.216 |
| S    |       | 5.50  |       |       | 0.216 |       |



## 5 Revision history

**Table 9. Document revision history**

| Date        | Revision | Changes                                                     |
|-------------|----------|-------------------------------------------------------------|
| 24-May-2007 | 1        | First release                                               |
| 04-Jan-2007 | 2        | Document status promoted from preliminary data to datasheet |

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